

Title (en)

ACTIVE PROBE FOR NEAR FIELD OPTICAL MICROSCOPY AND METHOD FOR ITS MANUFACTURE

Title (de)

AKTIVE SONDE FÜR OPTISCHE NAHFELD-MIKROSKOPIE UND DEREN HERSTELLUNGSVERFAHREN

Title (fr)

SONDE ACTIVE POUR MICROSCOPIE OPTIQUE EN CHAMP PROCHE ET SON PROCÉDÉ DE FABRICATION

Publication

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Application

EP 13712362 A 20130206

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Abstract (en)

[origin: WO2013121324A1] The invention relates to an active probe for near-field optical microscopy, characterized in that it comprises a metal or metallized tip (PM) at the apex of which a nanoscale body (BP) is located, said body comprising a polymer matrix capable of, or containing a host (MH) capable of, emitting, under illumination, light (SH) at a wavelength different from that of the illumination. Process for manufacturing such a probe. .

IPC 8 full level

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CPC (source: EP US)

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Citation (search report)

See references of WO 2013121324A1

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